

INTEGRATED CIRCUITS







### 74F174

### **FEATURES**

- Six edge-triggered D-type flip-flops
- Buffered common Clock
- Buffered, asynchronous Master Reset

### DESCRIPTION

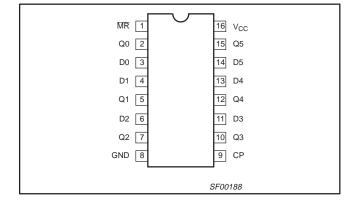
The 74F174 has six edge-triggered D-type flip-flops with individual D inputs and Q outputs. The common buffered Clock (CP) and Master Reset ( $\overline{\text{MR}}$ ) inputs load and reset (clear) all flip-flops simultaneously.

The register is fully edge-triggered. The state of each D input, one setup time before the Low-to-High clock transition is transferred to the corresponding flip-flop's Q output.

All Q outputs will be forced Low independent of Clock or Data inputs by a Low voltage level on the  $\overline{\text{MR}}$  input. The device is useful for applications where true outputs only are required, and the Clock and Master Reset are common to all storage elements.

TYPE	TYPICAL f <sub>MAX</sub>	TYPICAL SUPPLY CURRENT (TOTAL)
74F174	100MHz	35mA

### **PIN CONFIGURATION**



### **ORDERING INFORMATION**

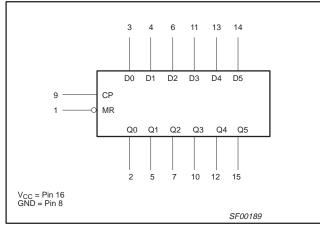
DESCRIPTION	$\begin{array}{l} \mbox{COMMERCIAL RANGE} \\ \mbox{V}_{CC} = 5V \pm 10\%, \\ \mbox{T}_{amb} = 0^{\circ}\mbox{C to } + 70^{\circ}\mbox{C} \end{array}$	PKG DWG #	
16-pin plastic DIP	N74F174N	SOT38-4	
16-pin plastic SO	N74F174D	SOT109-1	

### INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

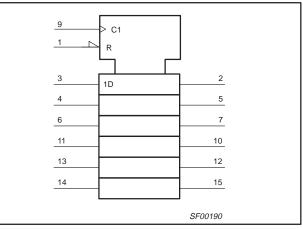
PINS	DESCRIPTION	74F (U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
D0–D5	Data inputs	1.0/1.0	20µA/0.6mA
СР	Clock Pulse input (active rising edge)	1.0/1.0	20µA/0.6mA
MR Master Reset input (active-Low)		1.0/1.0	20µA/0.6mA
Q0–Q5	Outputs	50/33	1.0mA/20mA

NOTE: One (1.0) FAST unit load is defined as: 20µA in the High state and 0.6mA in the Low state.

### LOGIC SYMBOL



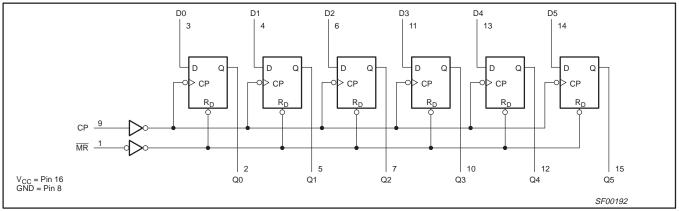
### **IEC/IEEE SYMBOL**



#### Product specification

### 74F174

### LOGIC DIAGRAM



#### **FUNCTION TABLE**

	INPUTS		OUTPUTS	OPERATING MODE
MR	CP	D	Qn	OPERATING MODE
L	Х	Х	L	Reset (clear)
н	$\uparrow$	h	н	Load "1"
н	$\uparrow$	I	L	Load "0"

H = High voltage level

L = Low voltage level

X = Don't care

 $\hat{\uparrow} = \text{Low-to-High Clock transition}$ h = High voltage level one set-up time prior to the Low-to-High Clock transition.

I = Low voltage level one set-up time prior to the Low-to-High Clock transition.

### **ABSOLUTE MAXIMUM RATINGS**

(Operation beyond the limits set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
V <sub>CC</sub>	Supply voltage	-0.5 to +7.0	V
V <sub>IN</sub>	Input voltage	-0.5 to +7.0	V
I <sub>IN</sub>	Input current	-30 to +5	mA
V <sub>OUT</sub>	Voltage applied to output in High output state	–0.5 to V <sub>CC</sub>	V
I <sub>OUT</sub>	Current applied to output in Low output state	40	mA
T <sub>amb</sub>	Operating free-air temperature range	0 to +70	°C
T <sub>stg</sub>	Storage temperature range	-65 to +150	°C

### **RECOMMENDED OPERATING CONDITIONS**

SYMBOL	PARAMETER		UNIT		
STWBUL	PARAMETER	MIN	NOM	MAX	UNIT
V <sub>CC</sub>	Supply voltage	4.5	5.0	5.5	V
V <sub>IH</sub>	High-level input voltage	2.0			V
V <sub>IL</sub>	Low-level input voltage			0.8	V
I <sub>IK</sub>	Input clamp current			-18	mA
I <sub>OH</sub>	High-level output current			-1	mA
I <sub>OL</sub>	Low-level output current			20	mA
T <sub>amb</sub>	Operating free-air temperature range	0		+70	°C

### 74F174

#### **DC ELECTRICAL CHARACTERISTICS**

(Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER	TEST CONDITION	TEST CONDITIONS <sup>1</sup>			LIMITS		
STMBOL	FARAMETER	TEST CONDITIC	N3.	MIN	TYP <sup>2</sup>	MAX	UNIT	
M		$V_{CC} = MIN, V_{IL} = MAX$	±10%V <sub>CC</sub>	2.5			V	
V <sub>OH</sub> High-level output voltage	$V_{IH} = MIN, I_{OH} = MAX$	±5%V <sub>CC</sub>	2.7	3.4		V		
M		$V_{CC} = MIN, V_{IL} = MAX$	±10%V <sub>CC</sub>		0.30	0.50	v	
V <sub>OL</sub> Low-level output voltage	Low-level output voltage	$V_{IH} = MIN, I_{OL} = MAX$	±5%V <sub>CC</sub>		0.30	0.50	V	
V <sub>IK</sub>	Input clamp voltage	$V_{CC} = MIN, I_I = I_{IK}$			-0.73	-1.2	V	
I <sub>I</sub>	Input current at maximum input voltage	$V_{CC} = MAX, V_I = 7.0V$				100	μΑ	
I <sub>IH</sub>	High-level input current	$V_{CC} = MAX, V_I = 2.7V$				20	μA	
I <sub>IL</sub>	Low-level input current	$V_{CC} = MAX, V_I = 0.5V$				-0.6	mA	
I <sub>OS</sub>	Short-circuit output current <sup>3</sup>	V <sub>CC</sub> = MAX		-60		-150	mA	
I <sub>CC</sub>	Supply current (total)	$V_{CC} = MAX, Dn = \overline{MR} =$	4.5V, CP = ↑		35	45	mA	

NOTES:

1. For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.

 All typical values are at V<sub>CC</sub> = 5V, T<sub>amb</sub> = 25°C.
Not more than one output should be shorted at a time. For testing I<sub>OS</sub>, the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, IOS tests should be performed last.

#### **AC ELECTRICAL CHARACTERISTICS**

		TEST CONDITION	LIMITS					
SYMBOL	PARAMETER		$V_{CC} = +5.0V$ $T_{amb} = +25^{\circ}C$ $C_{L} = 50pF, R_{L} = 500\Omega$			V <sub>CC</sub> = +5. T <sub>amb</sub> = 0°0 C <sub>L</sub> = 50pF,	UNIT	
			MIN	TYP	MAX	MIN	MAX	
f <sub>MAX</sub>	Maximum clock frequency	Waveform 1	80	100		80		MHz
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay CP to Qn	Waveform 1	3.5 4.5	5.5 6.0	8.0 10.0	3.5 4.5	9.0 11.0	ns
t <sub>PHL</sub>	Propagation delay MR to Qn	Waveform 2	5.0	8.5	14.0	5.0	15.0	ns

#### **AC SETUP REQUIREMENTS**

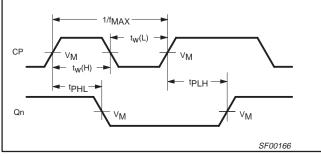
SYMBOL	PARAMETER	TEST CONDITION	$V_{CC}$ = +5.0V $T_{amb}$ = +25°C $C_L$ = 50pF, R <sub>L</sub> = 500Ω			V <sub>CC</sub> = +5. T <sub>amb</sub> = 0°C C <sub>L</sub> = 50pF,	UNIT	
			MIN	TYP	MAX	MIN	MAX	
t <sub>S</sub> (H) t <sub>S</sub> (L)	Setup time, High or Low Dn to CP	Waveform 3	4.0 4.0			4.0 4.0		ns
t <sub>h</sub> (H) t <sub>h</sub> (L)	Hold time, High or Low Dn to CP	Waveform 3	0.0 0.0			0.0 0.0		ns
t <sub>w</sub> (H) t <sub>w</sub> (L)	CP Pulse width, High or Low	Waveform 1	4.0 6.0			4.0 6.0		ns
t <sub>w</sub> (L)	MR Pulse width, Low	Waveform 2	5.0			5.0		ns
t <sub>REC</sub>	Recovery time, MR to CP	Waveform 2	5.0			5.0		ns

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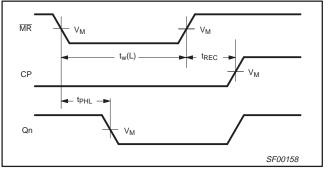
#### AC WAVEFORMS

For all waveforms,  $V_M = 1.5V$ .

The shaded areas indicate when the input is permitted to change for predictable output performance.

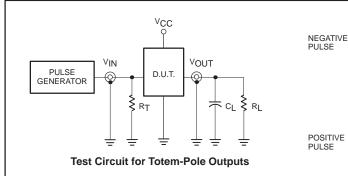


Waveform 1. Propagation Delay, Clock Input to Output, Clock Pulse Width, and Maximum Clock Frequency



Waveform 2. Master Reset Pulse Width, Master Reset to Output Delay and Master Reset to Clock recovery Time

#### **TEST CIRCUIT AND WAVEFORMS**



#### 10% 10% 0V tTHL (tf) tTLH (tr) tTLH (tr) tTHL (tf) AMP (V) 90% 90% POSITIVE PULSE ٧M ٧M 10% 10% 0V

90%

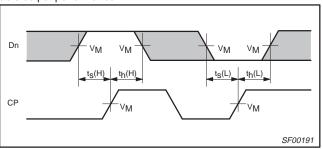
٧M

#### **DEFINITIONS:**

- R<sub>L</sub> = Load resistor;
- see AC ELECTRICAL CHARACTERISTICS for value.  $C_L$  = Load capacitance includes jig and probe capacitance;
- see AC ELECTRICAL CHARACTERISTICS for value.  $R_T$  = Termination resistance should be equal to  $Z_{OUT}$  of pulse generators.

Input Pulse Defini	tion
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fomily	INPUT PULSE REQUIREMENTS						
family	amplitude	V <sub>M</sub>	rep. rate	tw	t <sub>TLH</sub>	t <sub>THL</sub>	
74F	3.0V	1.5V	1MHz	500ns	2.5ns	2.5ns	



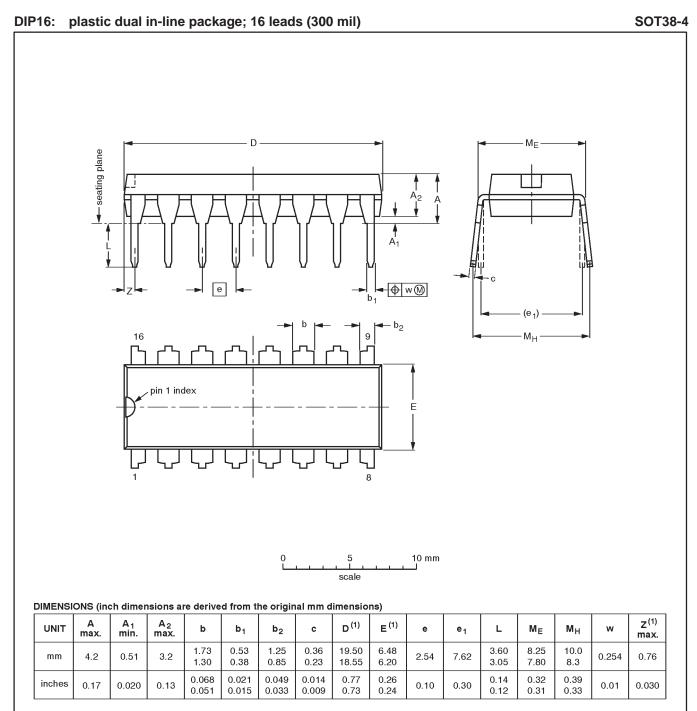
Waveform 3. Data Setup and Hold Times

AMP (V)

90%

٧N

74F174

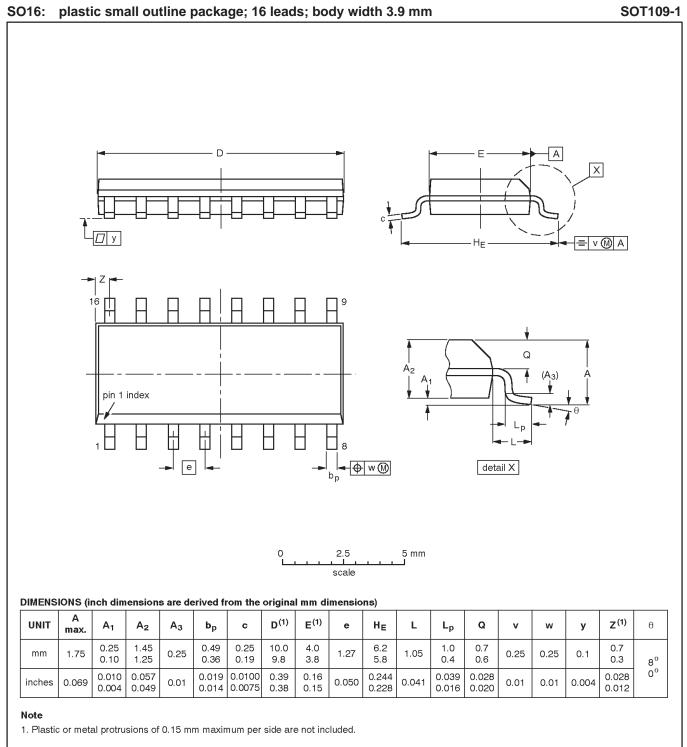


#### Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFER			ISSUE DATE	
VERSION	IEC	JEDEC			ISSUE DATE	
SOT38-4						<del>-92-11-17-</del> 95-01-14

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OUTLINE VERSION	REFERENCES				EUROPEAN	ISSUE DATE
	IEC	JEDEC	EIAJ		PROJECTION	1550E DATE
SOT109-1	076E07S	MS-012AC				<del>-95-01-23</del> 97-05-22
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# 74F174

#### Data sheet status

Data sheet status	Product status	Definition <sup>[1]</sup>	
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.	
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date Philips Semiconductors reserves the right to make chages at any time without notice in order to improve design and supply the best possible product.	
Product specification	Production	This data sheet contains final specifications. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible produ	

[1] Please consult the most recently issued datasheet before initiating or completing a design.

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Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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